- Contains Eight Flip-Flops With Single-Rail Outputs
- Buffered Clock and Direct Clear Inputs
- Individual Data Input to Each Flip-Flop
- Applications Include:

Buffer/Storage Registers Shift Registers Pattern Generators

description

These monolithic, positive-edge-triggered flipflops utilize TTL circuitry to implement D-type flip-flop logic with a direct clear input.

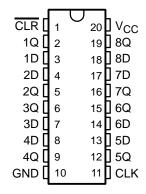
Information at the D inputs meeting the setup time requirements is transferred to the Q outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a particular voltage level and is not directly related to the transition time of the positive-going pulse. When the clock input is at either the high or low level, the D input signal has no effect ar the output.

These flip-flops are guaranteed to respond to clock frequencies ranging form 0 to 30 megahertz while maximum clock frequency is typically 40 megahertz. Typical power dissipation is 39 milliwatts per flip-flop for the '273 and 10 milliwatts for the 'LS273.

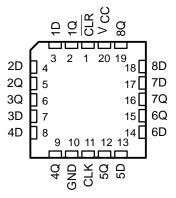
FUNCTION TABLE (each flip-flop)

	INPUTS		OUTPUT
CLEAR	CLOCK	D	Q
L	Х	Χ	L
Н	\uparrow	Н	Н
Н	\uparrow	L	L
Н	L	Χ	Q_0

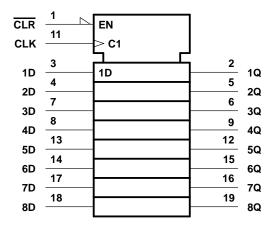
SN54273, SN74LS273 . . . J OR W PACKAGE SN74273 . . . N PACKAGE SN74LS273 . . . DW OR N PACKAGE (TOP VIEW)



SN54LS273 . . . FK PACKAGE (TOP VIEW)



logic symbol†

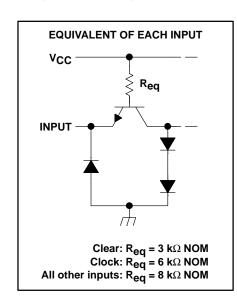


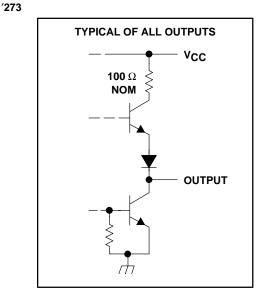
[†]This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the DW, J, N, and W packages.

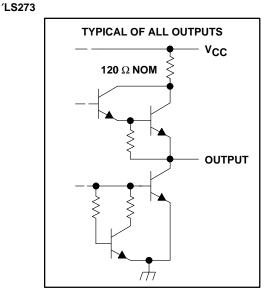


schematics of inputs and outputs

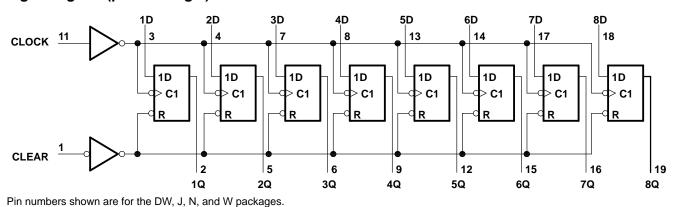




EQUIVALENT OF EACH INPUT VCC **20** $\mathbf{k}\Omega$ NOM INPUT -H



logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V _{CC} (see Note 1)	7 V
Input voltage	5.5 V
Operating free-air temperature range, T _A : SN54273	-55°C to 125°C
SN74273	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

		,	SN54273			SN74273		
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}		4.5	5	5.5	4.75	5	5.25	V
High-level output current, IOH				-800			-800	μΑ
Low-level output current, I _{OL}				16			16	mA
Clock frequency, f _{clock}		0		30	0		30	MHz
Width of clock or clear pulse, t _W		16.5			16.5			ns
Sotup time t	Data input	20↑			20↑			20
Setup time, t _{SU}	Clear inactive state	25↑			25↑			ns
Data hold time, t _h		5↑			5↑			ns
Operating free-air temperature, TA		-55		125	0		70	°C

[↑]The arrow indicates that the rising edge of the clock pulse is used for reference.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	_	TEST CONDITIONS [†]			TYP‡	MAX	UNIT
٧ _{IH}	High-level input voltage				2			V
VIL	Low-level input voltage						0.8	V
٧ıK	Input clamp voltage		V _{CC} = MIN,	$I_{I} = -12 \text{ mA}$			-1.5	V
Vон	High-level output voltage		V _{CC} = MIN, V _{IL} = 0.8 V,	V _{IH} = 2 V, I _{OH} = -800 μA	2.4	3.4		V
V _{OL}	Low-level output voltage		V _{CC} = MIN, V _{IL} = 0.8 V,	V _{IH} = 2 V, I _{OH} = 16 mA			0.4	V
IJ	Input current at maximum input voltage		V _{CC} = MAX,	V _I = 5.5 V			1	mA
l	High lovel input current	Clear	VMAY	V MAY V 0.4V			80	
'IH	High-level input current	Clock or D	$V_{CC} = MAX,$	V _I = 2.4 V			40	μΑ
l	Low lovel input ourrent	Clear	Voc - MAY	V _I = 0.4 V			-3.2	mA
ΊL	Low-level input current Clock or D		$V_{CC} = MAX,$	V = 0.4 V			-1.6	IIIA
los	Short-circuit output current§		V _{CC} = MAX		-18		-57	mA
Icc	Supply current		$V_{CC} = MAX$,	See Note 2		62	94	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

NOTE 2: With all outputs open and 4.5 V applied to all data and clear inputs, I_{CC} is measured after a momentary ground, then 4.5 V, is applied to clock.



 $^{^\}ddagger$ All typical values are at V_{CC} = 5 V, T_A = 25°C.

[§] Not more than one output should be shorted at a time.

SN54273, SN54LS273, SN74273, SN74LS273 OCTAL D-TYPE FLIP-FLOP WITH CLEAR

SDLS090 - OCTOBER 1976 - REVISED MARCH 1988

switching characteristics, V_{CC} = 5 V, T_A = 25°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
fmax	Maximum clock frequency		30	40		MHz
tPHL	Propagation delay time, high-to-low-level output from clear	C _L = 15 pF,		18	27	ns
^t PLH	Propagation delay time, low-to-high-level output from clock	R _L = 400 Ω , See Note 3		17	27	ns
tPHL	Propagation delay time, high-to-low-level output from clock			18	27	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V _{CC} (see Note 1)	7 V
Input voltage	7 V
Operating free-air temperature range, T _A : SN54LS273	. −55°C to 125°C
SN74LS273	0°C to 70°C
Storage temperature range	. −65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

		SI	N54LS27	3	SN74LS273			UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNII	
Supply voltage, V _{CC}		4.5	5	5.5	4.75	5	5.25	V	
High-level output current, IOH				-400			-400	μΑ	
Low-level output current, I _{OL}				4			8	mA	
Clock frequency, f _{clock}		0		30	0		30	MHz	
Width of clock or clear pulse, t _W		20			20			ns	
Sotup time t	Data input	20↑			20↑			20	
Setup time, t _{SU}	Clear inactive state	25↑			25↑			ns	
Data hold time, th		5↑			5↑			ns	
Operating free-air temperature, TA		-55		125	0		70	°C	

The arrow indicates that the rising edge of the clock pulse is used for reference.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONST		SI	N54LS27	'3	SN74LS273			UNIT		
	PARAMETER	TEST CONDITIONS:			MIN	TYP‡	MAX	MIN	TYP‡	MAX	ONII	
VIH	High-level input voltage				2			2			V	
V_{IL}	Low-level input voltage						0.7			8.0	V	
٧ıĸ	Input clamp voltage	$V_{CC} = MIN,$	I _I = –18 mA				-1.5			-1.5	V	
Vон	High-level output voltage	V _{CC} = MIN, V _{IL} = V _{IL} max,	$V_{IH} = 2 V,$ $I_{OH} = -400$	μΑ	2.5	3.4		2.7	3.4		V	
V/01	Low-level output voltage	V _{CC} = MIN,	V _{IH} = 2 V,	$I_{OL} = 4 \text{ mA}$		0.25	0.4		0.25	0.4	V	
VOL	Low-level output voltage	$V_{IL} = V_{IL} max$		$I_{OL} = 8 \text{ mA}$					0.35	0.5	٧	
lį	Input current at maximum input voltage	V _{CC} = MAX,	V _I = 7 V				0.1			0.1	mA	
ΙΗ	High-level input current	$V_{CC} = MAX$,	V _I = 2.7 V				20			20	μΑ	
Ι _Ι L	Low-level input current	$V_{CC} = MAX$,	$V_{I} = 0.4 V$				-0.4			-0.4	mA	
los	Short-circuit output current§	V _{CC} = MAX			-20		-100	-20		-100	mA	
ICC	Supply current	$V_{CC} = MAX$,	See Note 2			17	27		17	27	mA	

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

NOTE 2: With all outputs open and 4.5 V applied to all data and clear inputs, I_{CC} is measured after a momentary ground, then 4.5 V, is applied to clock.

switching characteristics, V_{CC} = 5 V, T_A = 25°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
fmax	Maximum clock frequency	_	30	40		MHz
tPHL	Propagation delay time, high-to-low-level output from clear	$C_L = 15 \text{ pF},$ $R_1 = 2 \text{ k}\Omega,$		18	27	ns
^t PLH	Propagation delay time, low-to-high-level output from clock	See Note 3		17	27	ns
^t PHL	Propagation delay time, high-to-low-level output from clock			18	27	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

[§] Not more than one output should be shorted at a time and duration of short circuit should not exceed one second.

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